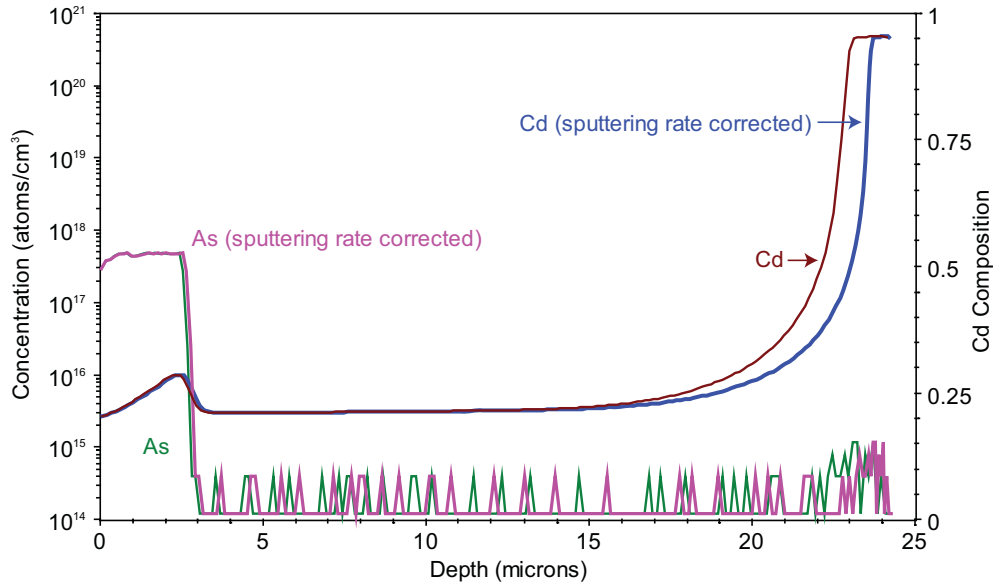




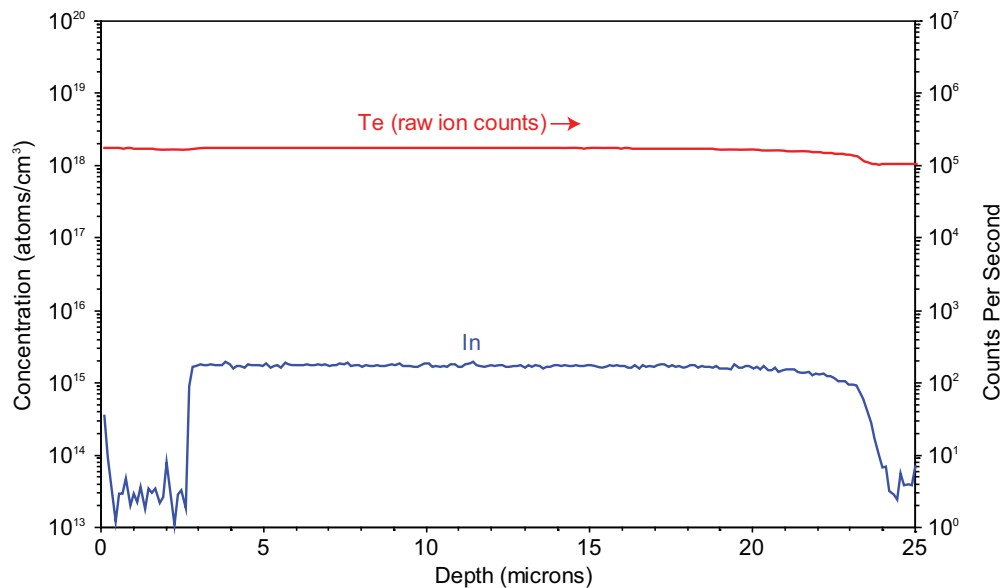
AN 442

## SIMS Characterization of HgCdTe Epilayer Structure

May 9, 2007 (Version 2.0)

**SIMS measurement of As and Cd of HgCdTe epilayer**

Point-by-Point sputtering rate correction on both As and Cd profiles provides more accurate layer thickness determination.

**SIMS measurement of In and Te in HgCdTe epilayer**

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